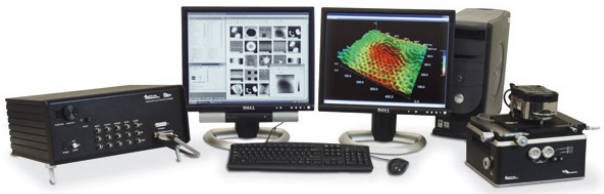
Atomic Force Microscope MFP-3D-SA

The Atomic Force Microscope (AFM), has been the instrument of choice for three dimensional measurements at the nanometer scale. With the MFP-3D Stand Alone (MFP-3D-SA) AFM, scientists can now choose a sensitive and precise AFM with the lowest noise performance that also includes a complete scientific software environment. The MFP-3D-SA is ideal for many applications including physics, material science, polymers, chemistry, nanolithography, bioscience, and quantitative nanoscale measurements. The MFP-3D has the flexibility to acquire your data, analyze it, and even make publication-ready graphics. Your imagination is your only limit.



Specifications:

MFP 3D AFM stand alone
- scan range XY:> 90 µm
- closed-loop position control with sensor noise < 1 nm (sensor non-linearity < 0,5 % at full scan)
- Z range:> 15 microns, sensor noise <0.4 nm in a 10 kHz BW
- operating modes: Contact, Non-Contact AC, Intermittent Contact (Q-Control, Phase, Amplitude), Force Mode, Force Volume, Lateral Force, Nanolithography, MFM and EFM
- Cantilever holder for operation in air and liquid environment (open configuration)
- Built-in cantilever force calibration capability based on thermal noise spectroscopy

Top View Optics Base
- Base for MFP-3D stand alone AFM including micrometer driven flat-travel slide stage for sample positioning and top-down optical access to tip and sample.

PFM – Piezo Force Module with the following items
- HVA 220 High Voltage Amplifier
- HV cantilever holder
- HV sample holder
- 70 Electri-Lever

Active Vibration Isolation
- Isolation: dynamic 0.6 Hz to 100 kHz
- Absorption: above 5 Hz:> 25 dB, above 10 Hz:> 40 dB

Acoustic Enclosure
- Enclosure designed for ultra-sensitive equipment, such as AFMs
- Up to 40 dB of acoustic isolation